

## MTP3N60 MTP3N60FI

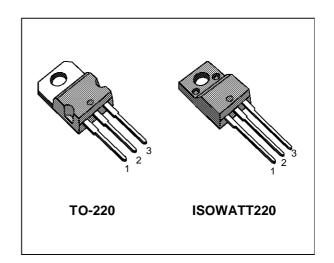
# N - CHANNEL ENHANCEMENT MODE POWER MOS TRANSISTOR

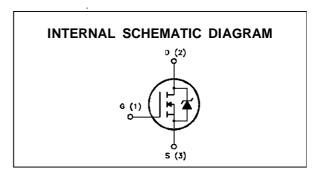
TYPE	V <sub>DSS</sub>	R <sub>DS(on)</sub>	I <sub>D</sub>
MTP3N60	600 V	< 2.5 Ω	3.9 A
MTP3N60FI	600 V	< 2.5 Ω	2.5 A

- TYPICAL  $R_{DS(on)} = 2 \Omega$
- AVALANCHE RUGGED TECHNOLOGY
- 100% AVALANCHE TESTED
- REPETITIVE AVALANCHE DATA AT 100°C
- APPLICATION ORIENTED CHARACTERIZATION

## **APPLICATIONS**

- HIGH CURRENT, HIGH SPEED SWITCHING
- SWITCH MODE POWER SUPPLIES (SMPS)
- CHOPPER REGULATORS, CONVERTERS, MOTOR CONTROL, LIGHTING FOR INDUSTRIAL AND CONSUMER ENVIRONMENT





## **ABSOLUTE MAXIMUM RATINGS**

Symbol	Parameter	Value		Unit
		MTP3N60	MTP3N60FI	
V <sub>DS</sub>	Drain-source Voltage (V <sub>GS</sub> = 0)	60	600	
$V_{DGR}$	Drain- gate Voltage ( $R_{GS} = 20 \text{ k}\Omega$ )	60	00	V
V <sub>G</sub> s	Gate-source Voltage	±	20	V
I <sub>D</sub>	Drain Current (continuous) at T <sub>c</sub> = 25 °C	3.9	2.5	Α
$I_{D}$	Drain Current (continuous) at T <sub>c</sub> = 100 °C	2.4	1.5	А
I <sub>DM</sub> (•)	Drain Current (pulsed)	14	14	Α
P <sub>tot</sub>	Total Dissipation at T <sub>c</sub> = 25 °C	100	35	W
	Derating Factor	0.8	0.28	W/°C
V <sub>ISO</sub>	Insulation Withstand Voltage (DC)			V
T <sub>stg</sub>	Storage Temperature	-65 to 150		°C
Tj	Max. Operating Junction Temperature	15	50	°C

<sup>(•)</sup> Pulse width limited by safe operating area

November 1996 1/10

## THERMAL DATA

			TO-220	ISOWATT220	
R <sub>thj-case</sub>	Thermal Resistance Junction-case	Max	1.25	3.57	°C/W
R <sub>thj-amb</sub> R <sub>thc-sink</sub> T <sub>I</sub>	Thermal Resistance Junction-ambient Thermal Resistance Case-sink Maximum Lead Temperature For Soldering Pu	Max Typ irpose	62 0. 30	5	°C/W °C/W °C

## **AVALANCHE CHARACTERISTICS**

Symbol	Parameter	Max Value	Unit
I <sub>AR</sub>	Avalanche Current, Repetitive or Not-Repetitive (pulse width limited by $T_j$ max, $\delta < 1\%$ )	3.9	А
Eas	Single Pulse Avalanche Energy (starting $T_j = 25$ °C, $I_D = I_{AR}$ , $V_{DD} = 25$ V)	300	mJ
E <sub>AR</sub>	Repetitive Avalanche Energy (pulse width limited by $T_j$ max, $\delta < 1\%$ )	7.7	mJ
I <sub>AR</sub>	Avalanche Current, Repetitive or Not-Repetitive $(T_c = 100  ^{\circ}\text{C}, \text{ pulse width limited by } T_j \text{ max, } \delta < 1\%)$	2.4	А

# **ELECTRICAL CHARACTERISTICS** ( $T_{case} = 25$ $^{\circ}C$ unless otherwise specified) OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source Breakdown Voltage	$I_D = 250 \ \mu A$ $V_{GS} = 0$	600			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current (V <sub>GS</sub> = 0)	$V_{DS} = Max Rating$ $V_{DS} = Max Rating x 0.8 T_c = 125 °C$			25 250	μA μA
I <sub>GSS</sub>	Gate-body Leakage Current (V <sub>DS</sub> = 0)	V <sub>GS</sub> = ± 20 V			± 100	nA

## ON (\*)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ $I_D = 1 \text{ mA}$	2	3	4.5	V
R <sub>DS(on)</sub>	Static Drain-source On Resistance	$V_{GS} = 10V  I_D = 1.5 \text{ A}$		2	2.5	Ω
I <sub>D(on)</sub>	On State Drain Current	$V_{DS} > I_{D(on)} \times R_{DS(on)max}$ $V_{GS} = 10 \text{ V}$	3.9			А

## **DYNAMIC**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
g <sub>fs</sub> (*)	Forward Transconductance	$V_{DS} > I_{D(on)} \times R_{DS(on)max}$ $I_D = 1.5 \text{ A}$	1.5	2.6		S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input Capacitance Output Capacitance Reverse Transfer Capacitance	V <sub>DS</sub> = 25 V f = 1 MHz V <sub>GS</sub> = 0		560 90 40	800 130 55	pF pF pF



## **ELECTRICAL CHARACTERISTICS** (continued)

## **SWITCHING ON**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub> t <sub>r</sub>	Turn-on Time Rise Time	$V_{DD} = 225 \text{ V}$ $I_D = 2.5 \text{ A}$ $R_G = 15 \Omega$ $V_{GS} = 10 \text{ V}$ (see test circuit, figure 3)		45 33	60 42	ns ns
(di/dt) <sub>on</sub>	Turn-on Current Slope	$V_{DD} = 480 \text{ V}$ $I_D = 4 \text{ A}$ $R_G = 15 \Omega$ $V_{GS} = 10 \text{ V}$ (see test circuit, figure 5)		200		A/μs
Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub>	Total Gate Charge Gate-Source Charge Gate-Drain Charge	V <sub>DD</sub> = 480 V I <sub>D</sub> = 4 A V <sub>GS</sub> = 10 V		43 6 21	55	nC nC nC

## **SWITCHING OFF**

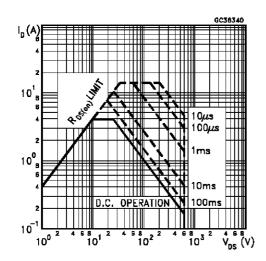
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t <sub>r(Voff)</sub>		$V_{DD} = 480 \text{ V}  I_{D} = 4 \text{ A}$		35	45	ns
tf	Fall Time	$R_G = 15 \Omega$ $V_{GS} = 10 V$		40	55	ns
t <sub>c</sub>	Cross-over Time	(see test circuit, figure 5)		60	75	ns

## SOURCE DRAIN DIODE

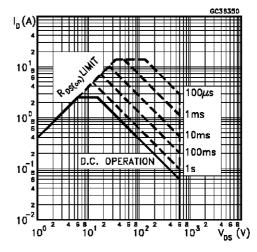
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub> I <sub>SDM</sub> (•)	Source-drain Current Source-drain Current (pulsed)				3.9 14	A A
Vsp (*)	Forward On Voltage	I <sub>SD</sub> = 3.9 A V <sub>GS</sub> = 0			2	V
t <sub>rr</sub>	Reverse Recovery Time	$I_{SD} = 4 \text{ A}$		420		ns
Qrr	Reverse Recovery Charge	(see test circuit, figure 5)		3.7		μС
$I_{RRM}$	Reverse Recovery Current			18		А

<sup>(\*)</sup> Pulsed: Pulse duration = 300 μs, duty cycle 1.5 %

## Safe Operating Areas For TO-220

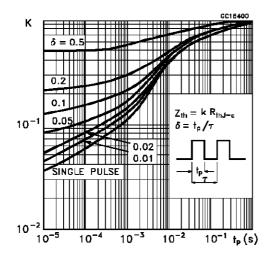


## Safe Operating Areas For ISOWATT220

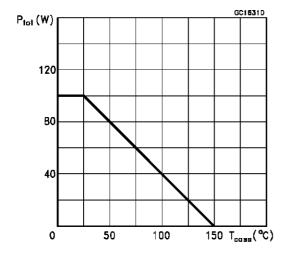


<sup>(•)</sup> Pulse width limited by safe operating area

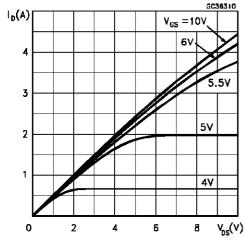
## Thermal Impedeance For TO-220



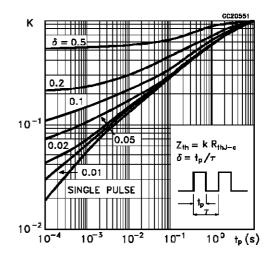
## Derating Curve For TO-220



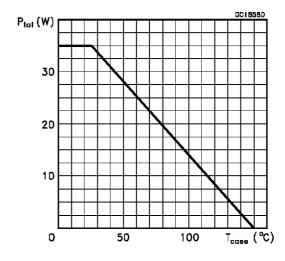
**Output Characteristics** 



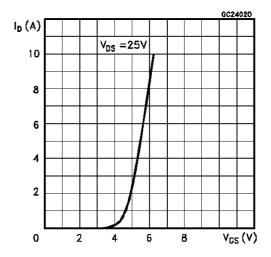
## Thermal Impedance For ISOWATT220



Derating Curve For ISOWATT220

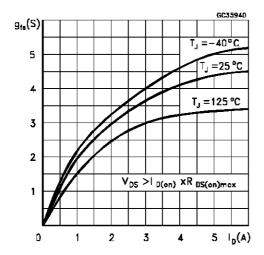


**Transfer Characteristics** 

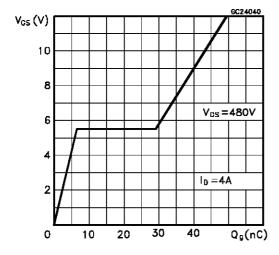


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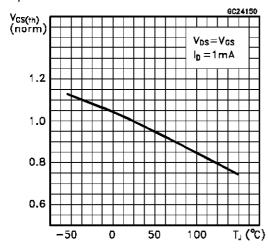
## Transconductance



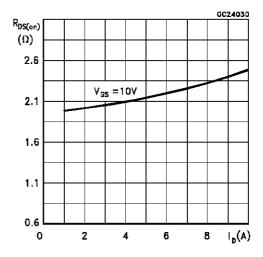
Gate Charge vs Gate-source Voltage



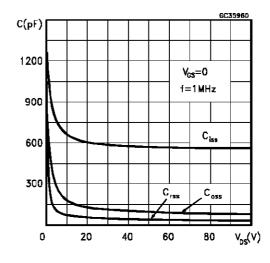
Normalized Gate Threshold Voltage vs Temperature



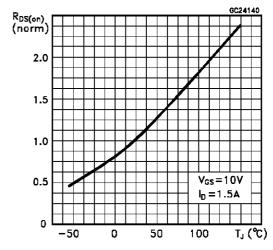
Static Drain-source On Resistance



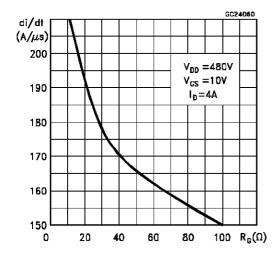
Capacitance Variations



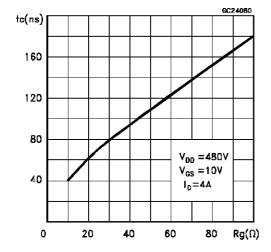
Normalized On Resistance vs Temperature



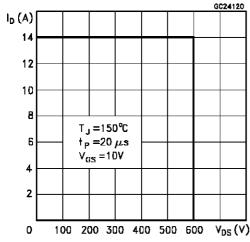
## Turn-on Current Slope



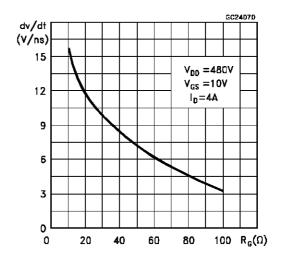
## Cross-over Time



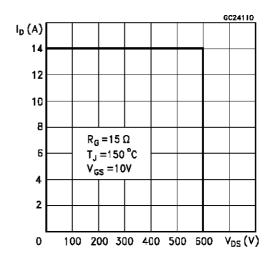
#### Accidental Overload Area



## Turn-off Drain-source Voltage Slope



## Switching Safe Operating Area



## Source-drain Diode Forward Characteristics

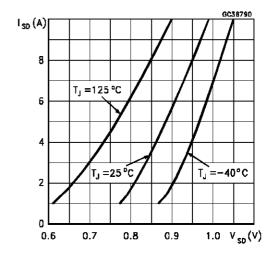
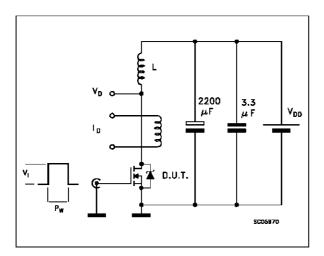
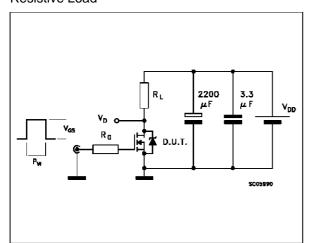


Fig. 1: Unclamped Inductive Load Test Circuits



**Fig. 3:** Switching Times Test Circuits For Resistive Load



**Fig. 5:** Test Circuit For Inductive Load Switching And Diode Reverse Recovery Time

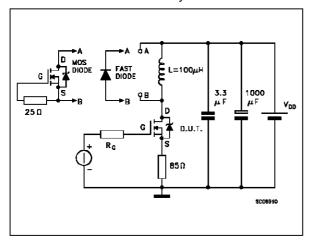


Fig. 2: Unclamped Inductive Waveforms

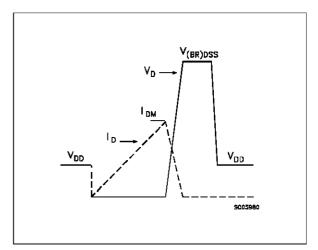
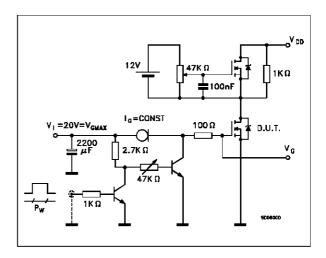


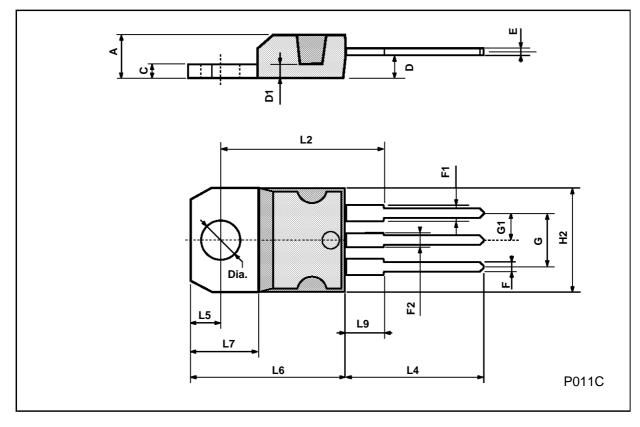
Fig. 4: Gate Charge Test Circuit



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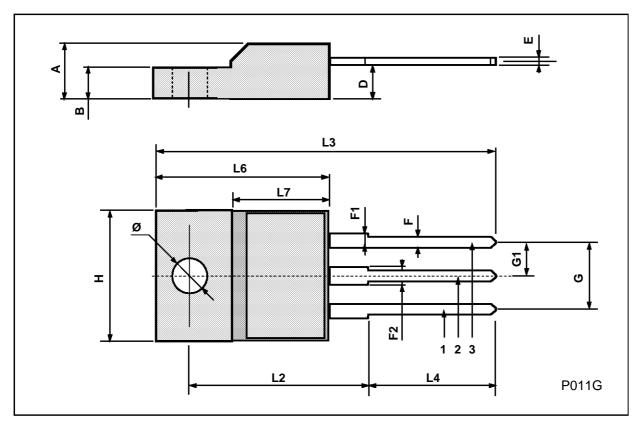
## **TO-220 MECHANICAL DATA**

DIM.		mm			inch	
DIIVI.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
А	4.40		4.60	0.173		0.181
С	1.23		1.32	0.048		0.051
D	2.40		2.72	0.094		0.107
D1		1.27			0.050	
Е	0.49		0.70	0.019		0.027
F	0.61		0.88	0.024		0.034
F1	1.14		1.70	0.044		0.067
F2	1.14		1.70	0.044		0.067
G	4.95		5.15	0.194		0.203
G1	2.4		2.7	0.094		0.106
H2	10.0		10.40	0.393		0.409
L2		16.4			0.645	
L4	13.0		14.0	0.511		0.551
L5	2.65		2.95	0.104		0.116
L6	15.25		15.75	0.600		0.620
L7	6.2		6.6	0.244		0.260
L9	3.5		3.93	0.137		0.154
DIA.	3.75		3.85	0.147		0.151



## **ISOWATT220 MECHANICAL DATA**

DIM.		mm			inch	
DIIVI.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
А	4.4		4.6	0.173		0.181
В	2.5		2.7	0.098		0.106
D	2.5		2.75	0.098		0.108
E	0.4		0.7	0.015		0.027
F	0.75		1	0.030		0.039
F1	1.15		1.7	0.045		0.067
F2	1.15		1.7	0.045		0.067
G	4.95		5.2	0.195		0.204
G1	2.4		2.7	0.094		0.106
Н	10		10.4	0.393		0.409
L2		16			0.630	
L3	28.6		30.6	1.126		1.204
L4	9.8		10.6	0.385		0.417
L6	15.9		16.4	0.626		0.645
L7	9		9.3	0.354		0.366
Ø	3		3.2	0.118		0.126



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